

# SILICON PLANAR EPITAXIAL TRANSISTOR

NPN transistor in a microminiature SMD package (SOT-223). Designed primarily for high-speed, saturated switching applications in industrial service.

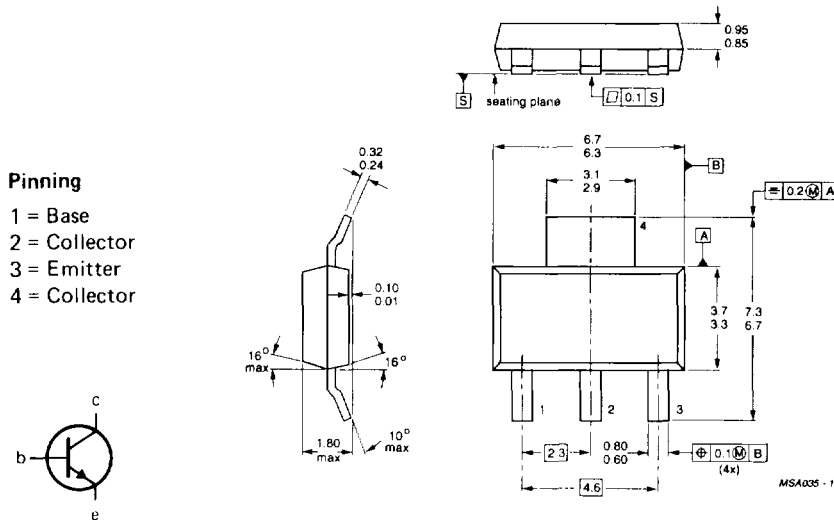
### QUICK REFERENCE DATA

Collector-base voltage (open emitter)	$V_{CBO}$	max.	60 V
Collector-emitter voltage (open base)	$V_{CEO}$	max.	40 V
Collector current (DC)	$I_C$	max.	200 mA
Total power dissipation at $T_{amb} = 25^\circ C$	$P_{tot}$	max.	1,5 W
Junction temperature	$T_j$	max.	150 $^\circ C$
DC current gain	$h_{FE}$	>	100
$I_C = 10 \text{ mA}; V_{CE} = 1 \text{ V}$		<	300
Transition frequency at $f = 100 \text{ MHz}$	$f_T$	>	300 MHz
$I_C = 10 \text{ mA}; V_{CE} = 20 \text{ V}$			
Storage time	$t_s$	<	200 ns
$I_{Con} = 10 \text{ mA}; I_{BOn} = -I_{Boff} = 1 \text{ mA}$			

### MECHANICAL DATA

Dimensions in mm

Fig. 1 SOT-223



**RATINGS**

Limiting values in accordance with the Absolute Maximum System (IEC 134)

Collector-base voltage (open emitter)	V <sub>CB0</sub>	max.	60 V
Collector-emitter voltage (open base)	V <sub>CEO</sub>	max.	40 V
Emitter-base voltage (open collector)	V <sub>EBO</sub>	max.	6 V
Collector current (DC)	I <sub>C</sub>	max.	200 mA
Total power dissipation at T <sub>amb</sub> = 25 °C*	P <sub>tot</sub>	max.	1,5 W
Storage temperature range	T <sub>stg</sub>		-65 to +150 °C
Junction temperature	T <sub>j</sub>	max.	150 °C

**THERMAL RESISTANCE**

From junction to ambient*	R <sub>th j-a</sub>	=	83,3 K/W
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**CHARACTERISTICS**

T<sub>j</sub> = 25 °C unless otherwise specified

Currents at reverse biased emitter junction

V <sub>CE</sub> = 30 V; -V <sub>BE</sub> = 3 V	I <sub>CEX</sub>	<	50 nA
	-I <sub>BEX</sub>	<	50 nA

Saturation voltages

I <sub>C</sub> = 10 mA; I <sub>B</sub> = 1 mA	V <sub>CEsat</sub>	<	200 mV
	V <sub>BEsat</sub>	650 to 850	mV

I <sub>C</sub> = 50 mA; I <sub>B</sub> = 5 mA	V <sub>CEsat</sub>	<	300 mV
	V <sub>BEsat</sub>	<	950 mV

DC current gain

I <sub>C</sub> = 0,1 mA; V <sub>CE</sub> = 1 V	h <sub>FE</sub>	>	40
I <sub>C</sub> = 1 mA; V <sub>CE</sub> = 1 V	h <sub>FE</sub>	>	70
I <sub>C</sub> = 10 mA; V <sub>CE</sub> = 1 V	h <sub>FE</sub>	>	100
I <sub>C</sub> = 50 mA; V <sub>CE</sub> = 1 V	h <sub>FE</sub>	<	300
I <sub>C</sub> = 100 mA; V <sub>CE</sub> = 1 V	h <sub>FE</sub>	>	60
	h <sub>FE</sub>	>	30

Collector capacitance at 100 kHz ≤ f ≤ 1 MHz

I <sub>E</sub> = I <sub>e</sub> = 0; V <sub>CB</sub> = 5 V	C <sub>c</sub>	<	4,0 pF
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Emitter capacitance at 100 kHz ≤ f ≤ 1 MHz

I <sub>C</sub> = I <sub>c</sub> = 0; V <sub>EB</sub> = 0,5 V	C <sub>e</sub>	<	8,0 pF
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Transition frequency at f = 100 MHz

I <sub>C</sub> = 10 mA; V <sub>CE</sub> = 20 V; T <sub>amb</sub> = 25 °C	f <sub>T</sub>	>	300 MHz
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Noise figure at R<sub>S</sub> = 1 kΩ

I <sub>C</sub> = 100 μA; V <sub>CE</sub> = 5 V	F	<	5,0 dB
f = 10 Hz to 15,7 kHz; T <sub>amb</sub> = 25 °C			

\* Device mounted on an epoxy printed circuit board 40 mm x 40 mm x 1,5 mm; mounting pad for the collector lead min. 6 cm<sup>2</sup>.

**Switching times**

Turn-on time (see Figs 2 and 3) when switched from  $-V_{BEoff} = 0,5 \text{ V}$  to  $I_{Con} = 10 \text{ mA}$ ;  $I_{Bon} = 1 \text{ mA}$

Delay time

Rise time

$$t_d < 35 \text{ ns}$$

$$t_r < 35 \text{ ns}$$

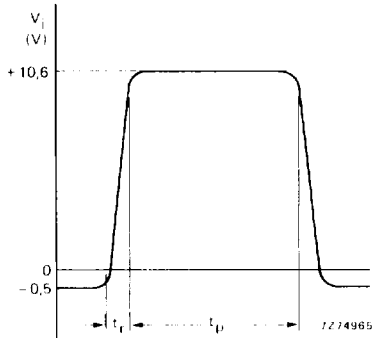


Fig. 2 Input waveform;  $t_r < 1 \text{ ns}$ ;  $t_p = 300 \text{ ns}$ ;  $\delta = 0,02$ .

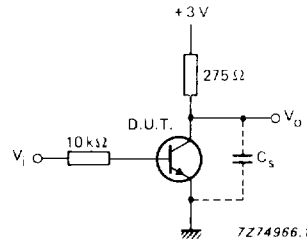


Fig. 3 Delay and rise time test circuit; total shunt capacitance of test jig and connectors  $C_s < 4 \text{ pF}$ ; scope impedance =  $10 \text{ M}\Omega$ .

Turn-off time (see Figs 4 and 5)

$I_{Con} = 10 \text{ mA}$ ;  $I_{Bon} = -I_{Boff} = 1 \text{ mA}$

Storage time

Fall time

$$t_s < 200 \text{ ns}$$

$$t_f < 50 \text{ ns}$$

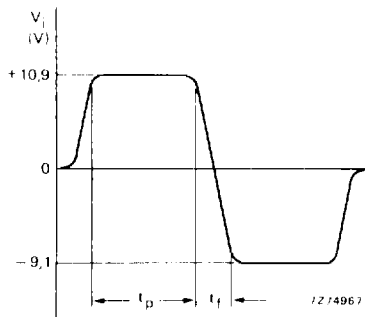


Fig. 4 Input waveform;  $t_f < 1 \text{ ns}$ ;  $10 \mu\text{s} < t_p < 500 \mu\text{s}$ ;  $\delta = 0,02$ .

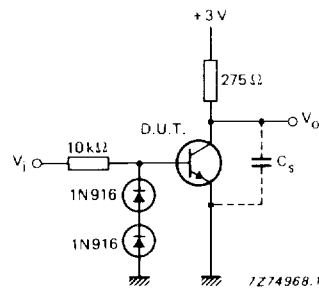


Fig. 5 Storage and fall time test circuit; total shunt capacitance of test jig and connectors  $C_s < 4 \text{ pF}$ ; scope impedance =  $10 \text{ M}\Omega$ .